

**Search Notes**

Application/Control No.

10/761,486

Examiner

Maria Veronica D. Ewald

Applicant(s)/Patent under  
Reexamination

HARPER ET AL.

Art Unit

1722

**SEARCHED**

Class	Subclass	Date	Examiner
425	384,385	5/8/2006	MVE
425	388,143	5/9/2006	MVE
425	808,810	5/9/2006	MVE
425	387.1,398	5/8/2006	MVE
425	400,403.1	5/8/2006	MVE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search	5/9/2006	MVE
Consulted with Examiner Thu-khanh Nguyen, AU 1722	5/8/2006	MVE
Also conducted text search in EAST (see attached search history)	5/9/2006	MVE